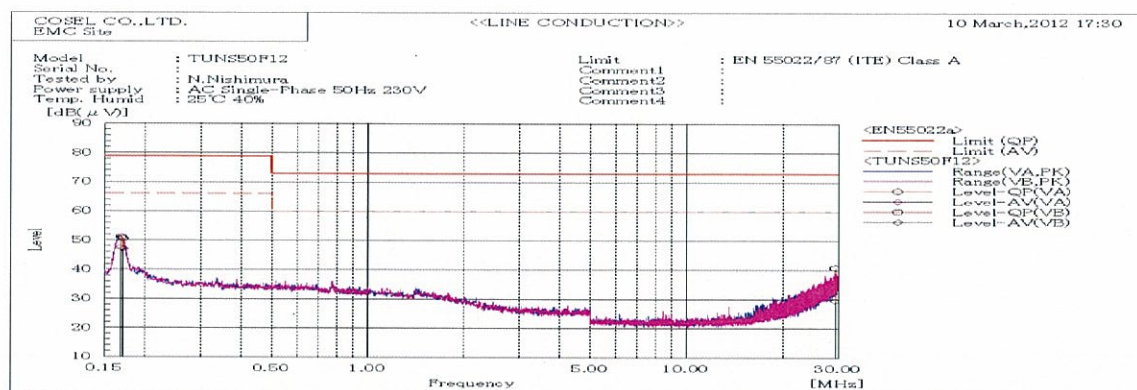
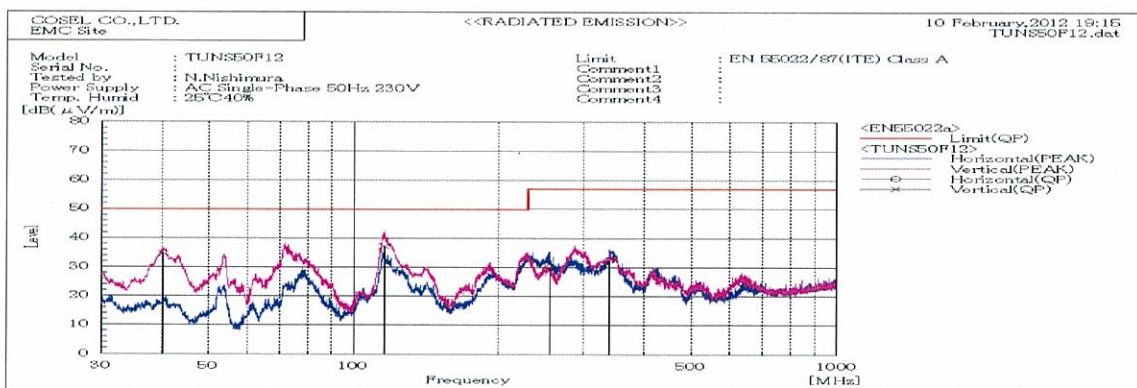


DATA SHEET			Date	17-Apr-12
Model	TUN50F12		Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission		Humid.	40 %RH
			Tested by	N.Nishimura



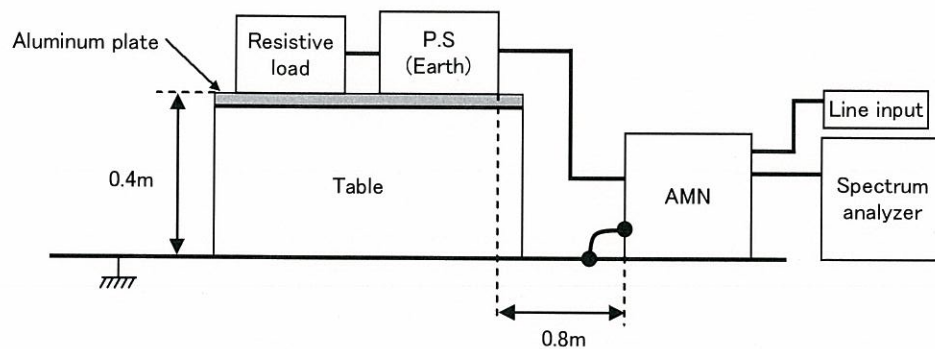
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.17061	VA	40.4	36.9	10.2	50.6	47.1	79	66	28.4	18.9	Pass
0.16851	VB	40.9	37.3	10.2	51.1	47.5	79	66	27.9	18.5	Pass
29.21665	VB	29.8	18.6	11	40.8	29.6	73	60	32.2	30.4	Pass



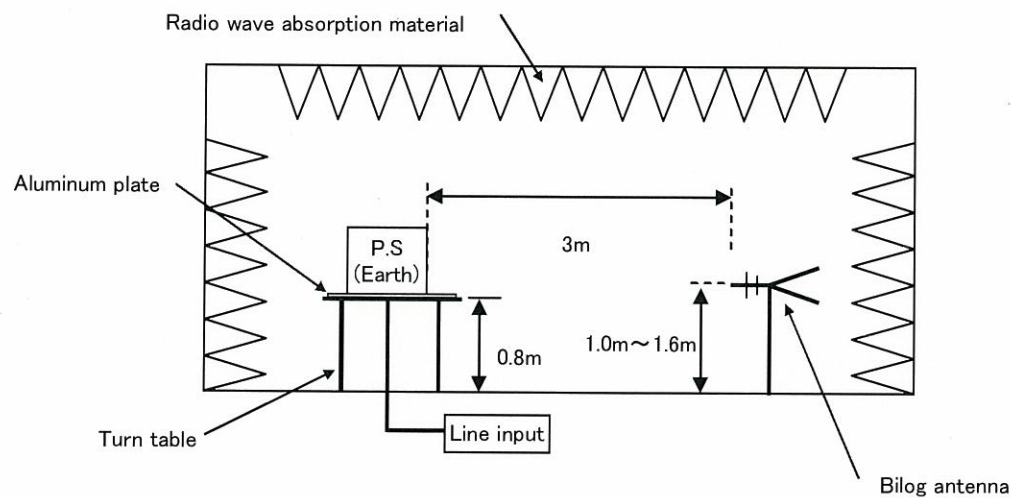
Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Height cm	Angle deg	Pass/ Fail
			QP			QP	QP	QP			
40.319	V	Stable	50.2	-15.6		34.6	50	15.4	103	49	Pass
115.377	V	Stable	55.3	-18.2		37.1	50	12.9	144	17	Pass
255.693	H	Stable	48.6	-18.3		30.3	57	26.7	126	101	Pass
339.228	H	Stable	46.9	-14.4		32.5	57	24.5	106	112	Pass

DATA SHEET		Date	17-Apr-12
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	N.Nishimura

1. Line conduction



2. Radiated emission

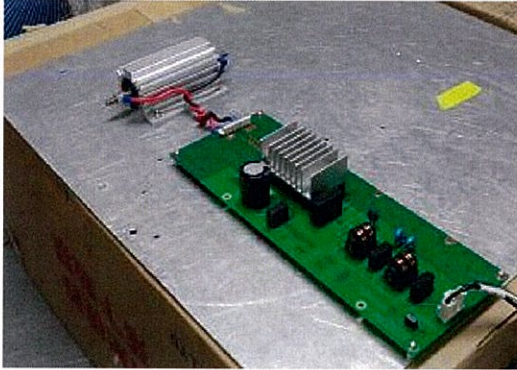


Test: EMI

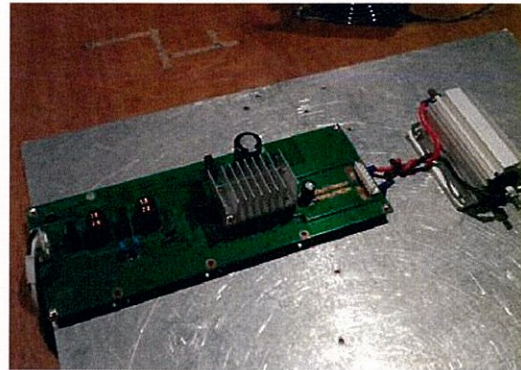
Model Name: TUNS50F Series

○ Photographs of Test Set-Up

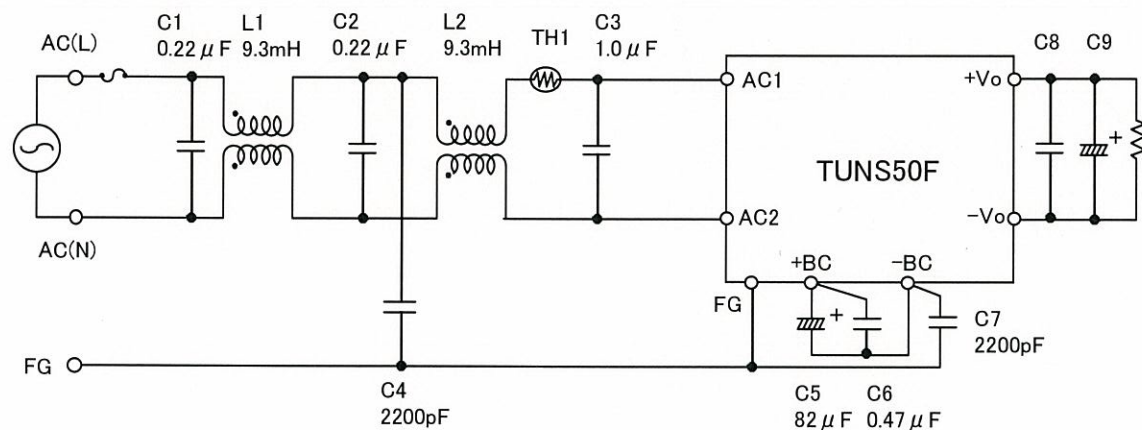
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2 : SS11VL-R10093(NEC TOKIN)

TH1 : 5D2-08(SEMITEC)

C8 : TUNS50F05 10 μF

TUNS50F12 10 μF

TUNS50F24 4.7 μF

C9 : TUNS50F05 2200 μF

TUNS50F12 470 μF

TUNS50F24 220 μF